

Example:

n-type silicon, dopant  $N_D = 10^{17}/\text{cm}^3$ ,  
find electron and hole concentration (room-temp)

$N_D$ : concentration of the donor

$$N_D = n_n \rightarrow 10^{17}/\text{cm}^3$$

concentration  
of electrons  
n-type

$$n_n \cdot p_n = n_i^2 = (1.5 \times 10^{10})^2$$
$$p_n = \frac{n_i^2}{n_n} = \frac{(1.5 \times 10^{10})^2}{10^{17}}$$
$$= 2.25 \times 10^3 \text{ carriers}/\text{cm}^3$$

①

P-type . . .  $N_A = 10^{17} / \text{cm}^3$

find . . . . . (room-temp).

$$N_A = P_p = 10^{17} / \text{cm}^3$$

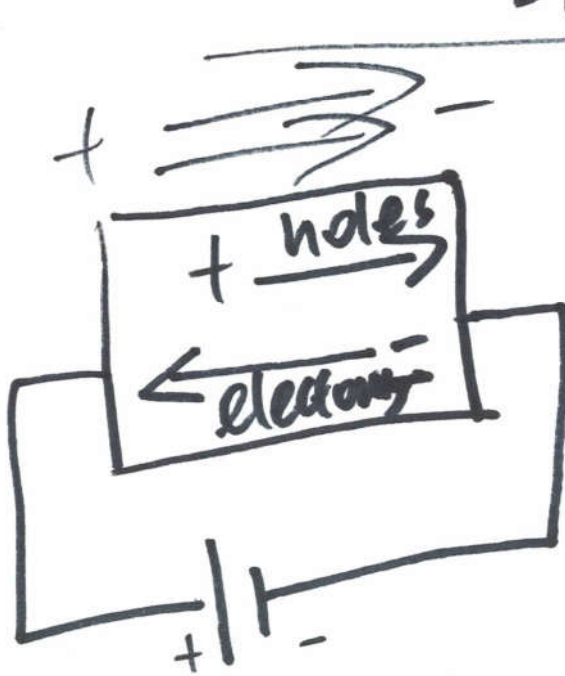
concentration P-type  
of holes.

$$P_p \cdot n_p = n_i^2$$

$$n_p = \frac{n_i^2}{P_p} = 2.25 \times 10^3 \text{ carriers/cm}^3$$

2

# Drift Current in Semiconductors



velocities  $\left\{ \begin{array}{l} \frac{m/s}{V} = \frac{m}{V \cdot s} = \frac{m \cdot 1}{V \cdot s} \\ v_{n\text{-drift}} = -\mu_n \cdot E \\ v_{p\text{-drift}} = \mu_p \cdot E \end{array} \right.$

$\left\{ \begin{array}{l} \mu_n : \text{electron mobility} \\ \mu_p : \text{hole mobility} \end{array} \right.$

$$\mu_n > \mu_p$$

electrons move faster! easier than holes.

Resistivity:

$$\rho = \frac{1}{q(p\mu_p + n\mu_n)}$$

Conductivity:

$$\sigma = q(p\mu_p + n\mu_n) = \frac{1}{\rho}$$

$q$ : magnitude of electron charge  
 $1.6 \times 10^{-19} \text{ C}$

Intrinsic Silicon:

Given:  $p = n = n_i = 1.5 \times 10^{10} / \text{cm}^3$ ,  $\mu_n = 1350 \text{ cm}^2/\text{V}$ ,  
 $\mu_p = 480 \text{ cm}^2/\text{V}$ ,  $\rho$ ?

$$\rho = \frac{1}{q(\mu_n n + \mu_p p)}$$
$$= \frac{1}{1.6 \times 10^{-19} (1350 \cdot 1.5 \times 10^{10} + 480 \cdot 1.5 \times 10^{10})}$$
$$= \dots \dots \dots$$

~~P.L~~



P-type

Given:  $N_A = 10^{16} / \text{cm}^3$ ,  $\mu_n = 1110 \text{ cm}^2/\text{V}$ ,

$\mu_p = 400 \text{ cm}^2/\text{V}$ ,  $\rho$ ?

$$\rho = \frac{1}{q(\mu_n n + \mu_p p)}$$

$$p = N_A$$

$$n = \frac{n_i^2}{p} = \frac{(1.5 \times 10^{10})^2}{10^{16}}$$

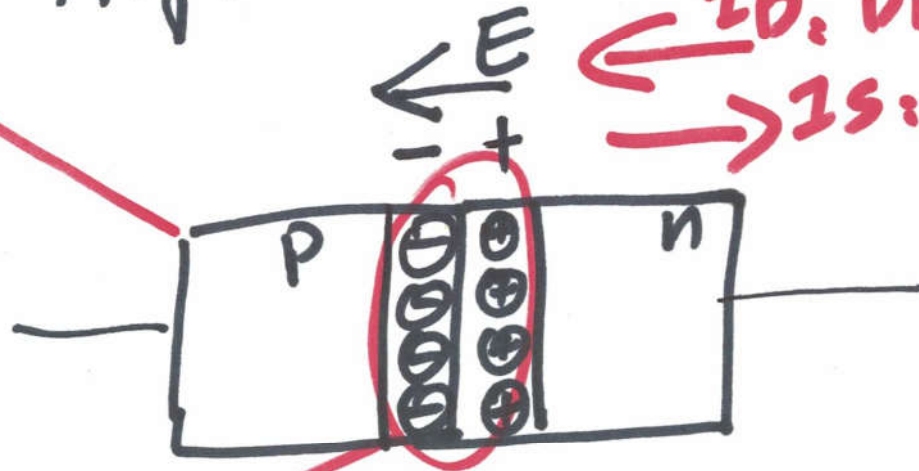
$$= \boxed{\phantom{000000}} \text{ carriers/cm}^3$$

(b)

# P n Junction

## Diffusion Current

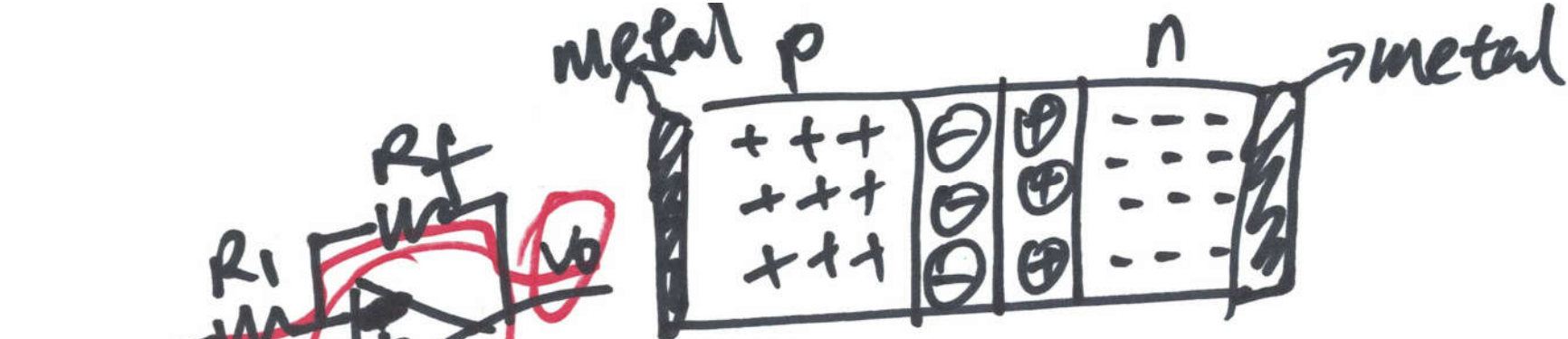
High Concentration  $\rightarrow$  Low Concentration



$I_D$ : Drift Current.  
 $I_S$ : diffusion current

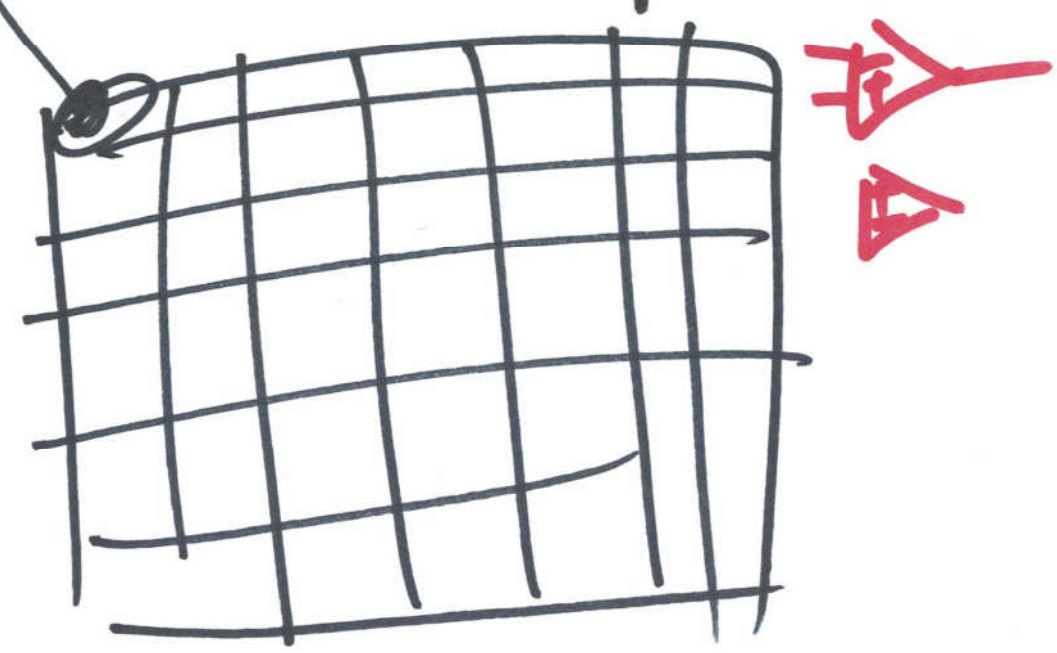
$\Delta$  will stop at a thickness.

$\Delta$  Depletion region form an Electric Field  $E$ , and opposes more diffusion to happen.



TIA Transimpedance Amplifier

CMOS-Imager



⑧